



INTERNATIONAL
ELECTROTECHNICAL
COMMISSION

IEC TC 113 Nanotechnology Standardization for Electrical and Electronic Products and Systems

Expectations and Partners' Motivation

Nanotechnology Documentary Standards Workshop,
NIST, Gaithersburg, MD, February 26-28, 2008

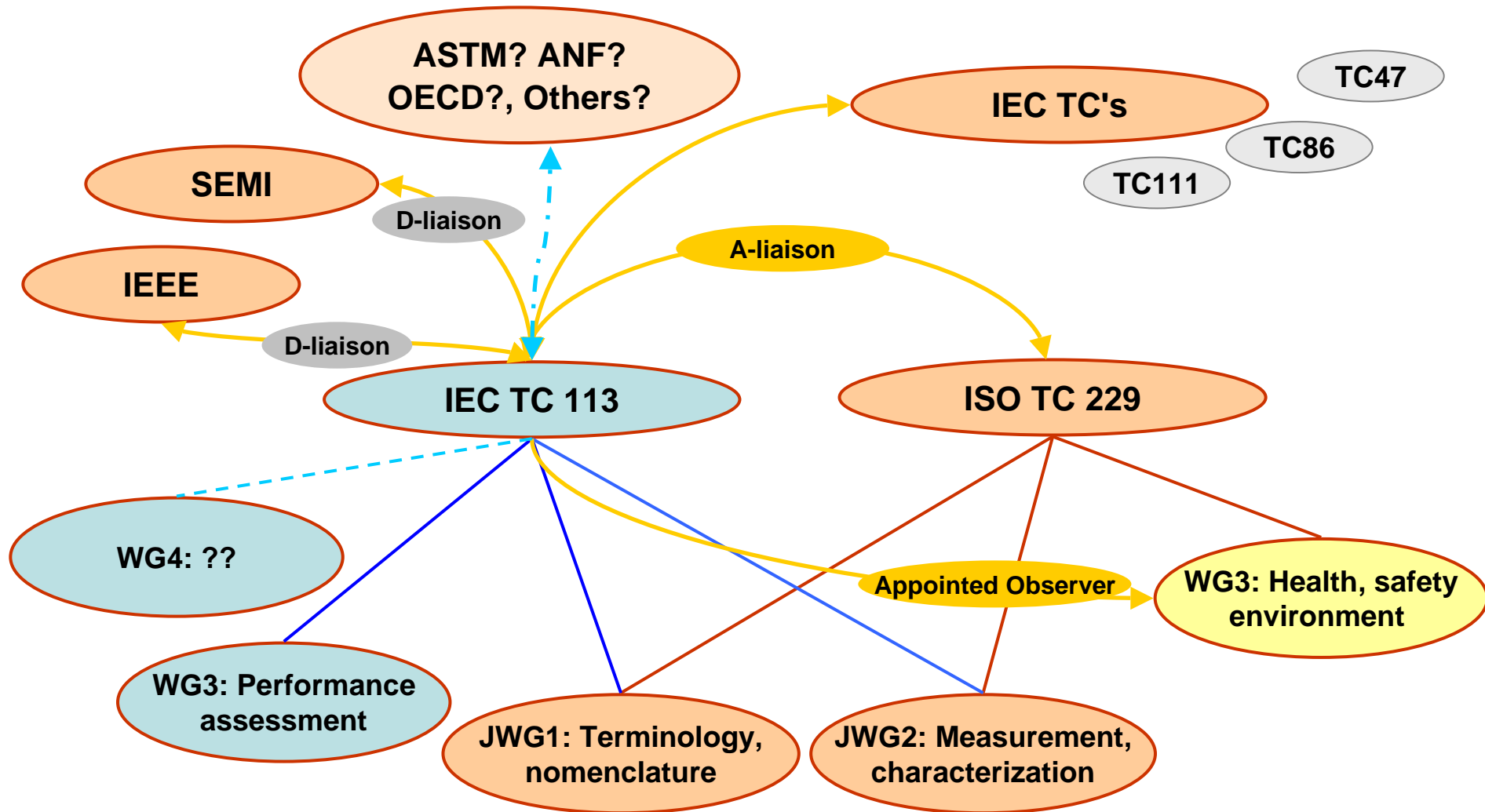
J. Thomas Chapin, Ph.D., Chair

Norbert Fabricius, Ph.D., Secretary

*International Workshop on Documentary Standards for
Measurement and Characterization in Nanotechnologies*



International Standardisation in Nanotechnology



D-Liaisons: SEMI & IEEE (under SMB ballot)

International Workshop on Documentary Standards for Measurement and Characterization in Nanotechnologies

IEC TC 113 WG3 - Market demand or technology pull - emphasis on performance, reliability, process control, durability, disposal, and recycling

→ **Nano-function attributes – conductivity, resistance, failure rates, strength.**

Diffuse Moving Boundary

IEC TC 113 ↘ **JWG2 -- Technology push from R&D to innovation - emphasis on metrology**

ISO TC 229 ↗

→ **Nano-composition attributes – elemental make-up, dimensions, structure, morphology.**